

<b>Notice of References Cited</b>	Application/Control No. 09/890,597		Applicant(s)/Patent Under Reexamination DULTZ ET AL.	
	Examiner Hanh Phan		Art Unit 2613	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,130,766	10-2000	Cao, Xiang-Dong	398/147
*	C	US-5,371,597	12-1994	Favin et al.	356/367
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.